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# 1 [Data and memory optimization techniques for embedded systems](#)

P. R. Panda, F. Catthoor, N. D. Dutt, K. Danckaert, E. Brockmeyer, C. Kulkarni, A.

Vandercappelle, P. G. Kjeldsberg

April 2001 **ACM Transactions on Design Automation of Electronic Systems (TODAES)**,

Volume 6 Issue 2

Full text available: pdf(339.91 KB)

Additional Information: [full citation](#), [abstract](#), [references](#), [citations](#), [index terms](#)

We present a survey of the state-of-the-art techniques used in performing data and memory-related optimizations in embedded systems. The optimizations are targeted directly or indirectly at the memory subsystem, and impact one or more out of three important cost metrics: area, performance, and power dissipation of the resulting implementation. We first examine architecture-independent optimizations in the form of code transformations. We next cover a broad spectrum of optimizati ...

**Keywords:** DRAM, SRAM, address generation, allocation, architecture exploration, code transformation, data cache, data optimization, high-level synthesis, memory architecture customization, memory power dissipation, register file, size estimation, survey

# 2 [Fast detection of communication patterns in distributed executions](#)

Thomas Kunz, Michiel F. H. Seuren

November 1997 **Proceedings of the 1997 conference of the Centre for Advanced Studies on Collaborative research**

Full text available: pdf(4.21 MB)

Additional Information: [full citation](#), [abstract](#), [references](#), [index terms](#)

Understanding distributed applications is a tedious and difficult task. Visualizations based on process-time diagrams are often used to obtain a better understanding of the execution of the application. The visualization tool we use is Poet, an event tracer developed at the University of Waterloo. However, these diagrams are often very complex and do not provide the user with the desired overview of the application. In our experience, such tools display repeated occurrences of non-trivial commun ...

# 3 [The effectiveness of multiple hardware contexts](#)

Radhika Thekkath, Susan J. Eggers

November 1994 **Proceedings of the sixth international conference on Architectural****support for programming languages and operating systems**, Volume 29 , 28

Issue 11 , 5

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